Correction to: Novel capacitance evaluation model for microelectromechanical switch considering fringe and effect of holes in pull-up and pull-down conditions

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The original version of this article unfortunately contains a typing error. Last term of Eq. (5) and brackets were incorrectly placed while article preparation and the correct version of that equation should be

$$C_{1,u} = \frac{\epsilon_0 A}{g_0 + \frac{t_d}{\epsilon_r}} + \frac{2 \epsilon_r W}{\pi} \left[\ln \left(\frac{\pi w}{g_0 + \frac{t_d}{\epsilon_r}} \right) + \ln \left(\left(1 + \frac{2t_b}{g_0 + \frac{t_d}{\epsilon_r}} \right) + 2 \sqrt{\left(\frac{t_b}{g_0 + \frac{t_d}{\epsilon_r}} + \frac{t_b^2}{\left(g_0 + \frac{t_d}{\epsilon_r} \right)^2} \right)} \right) \right]$$

The changes will be applied subsequently in the Eqs. (6), (7), (8), (9), (10), (12) and (13).

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